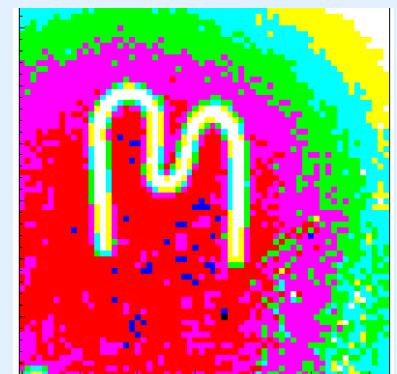


Computed tomography using the Medipix1 chip

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Outline

- Detection system
- Principles of Computed Tomography (CT)
- Conventional CT images
- CT using the energy threshold of the Medipix1
 - Effects on contrast
 - Similar non-CT measurements and simulations
- CT with a large virtual detector
- Conclusion and Outlook

Medipix1 – our detector

- The Medipix1-system was developed by the Medipix-Collaboration mainly at CERN
- It is a hybrid pixel detector; we use $300\ \mu\text{m}$ Si as conversion material
- Characteristic properties:
 64×64 pixels each of size $(170\ \mu\text{m})^2$ with a 15bit counter
- Single photon counting device
- Energy sensitive due to a threshold discriminator
- Threshold discriminator can be fine-tuned via a 3bit-DAC

Data acquisition system

- X-ray tube with Mo anode, tube voltage: 20 – 40 kV, focal spot $\approx 0.4 \times 0.6 \text{ mm}^2$
- Medipix1 is controlled via MUROS and Medisoft
- Translation and rotation stages are required for CT measurements
- Because we do hundreds of measurements we have an automation system which controls tube, MediSoft and the stages

Principles of Computed Tomography (CT)

- In contrast to medical CT we rotate the object
- For a complete CT dataset projections of the object in an angular range of at least 180° are necessary

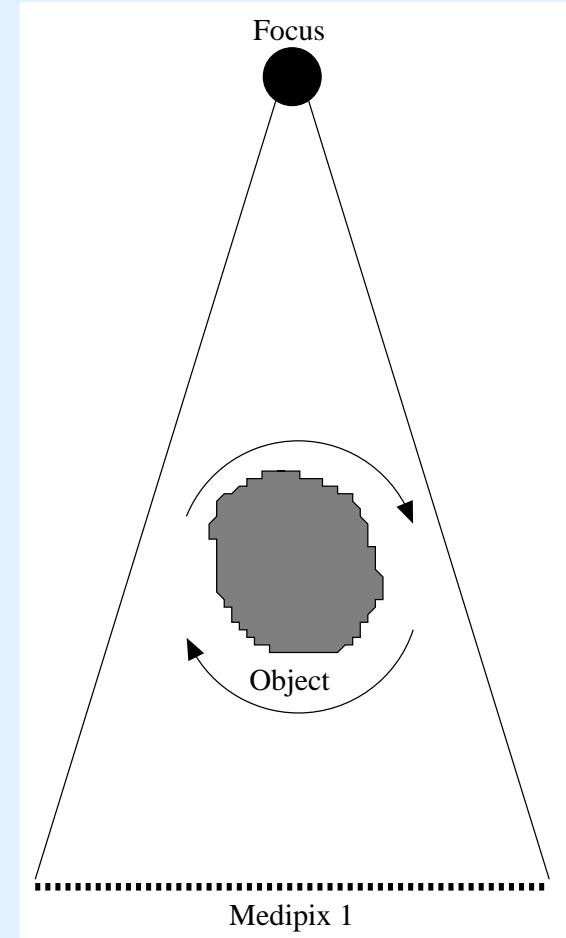
- Measured value in each detector element:

$$I = I_0 \exp \left[- \int_{\text{ray}} \mu(x, y, E_{\text{eff}}) ds \right]$$

- Input for reconstruction (filtered back-projection):

$$\int_{\text{ray}} \mu(x, y, E_{\text{eff}}) ds$$

- The reconstructed variable is $\mu(x, y, E_{\text{eff}}) = \mu_{\text{eff}}(x, y)$



Principles of Computed Tomography (CT)

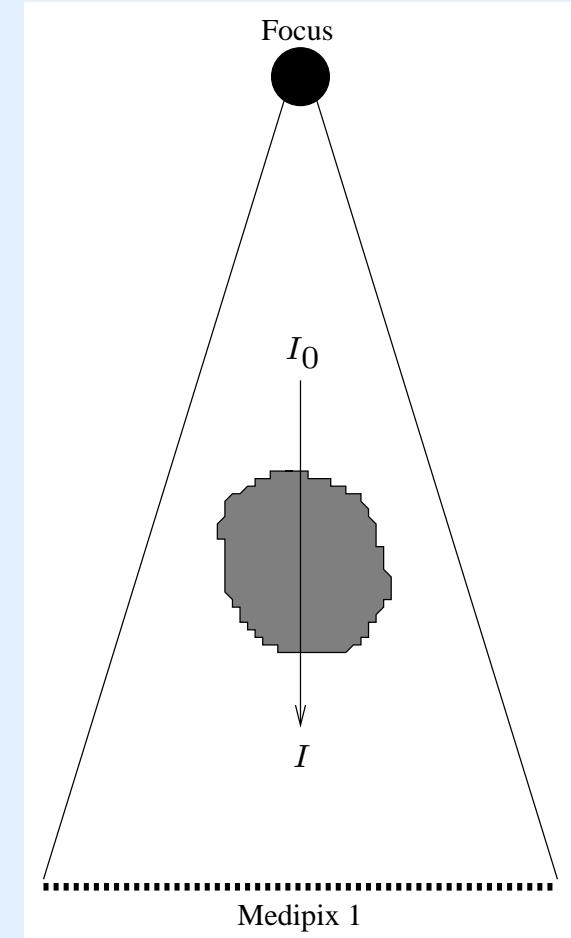
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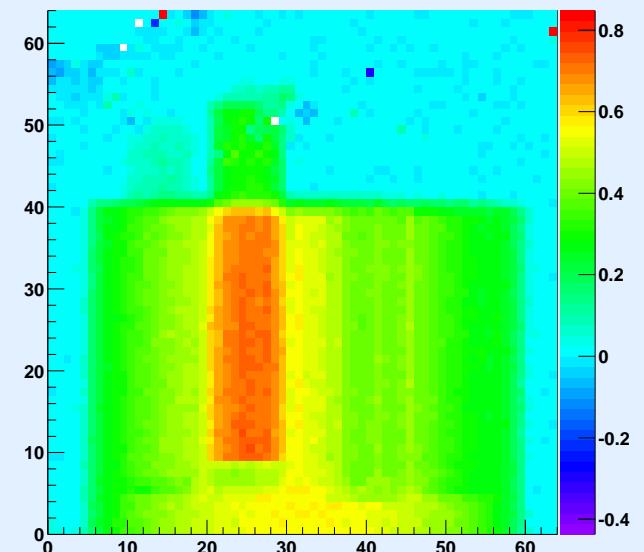
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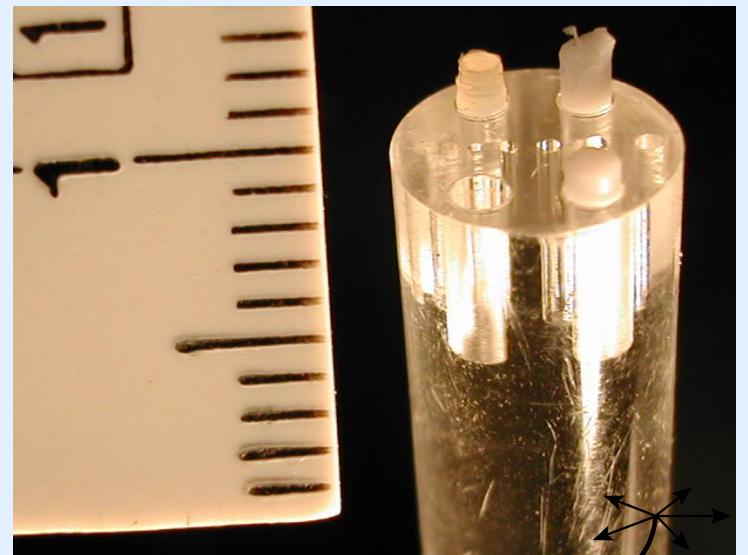
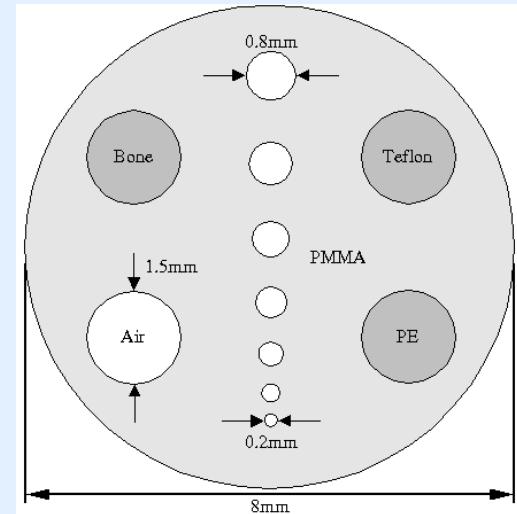
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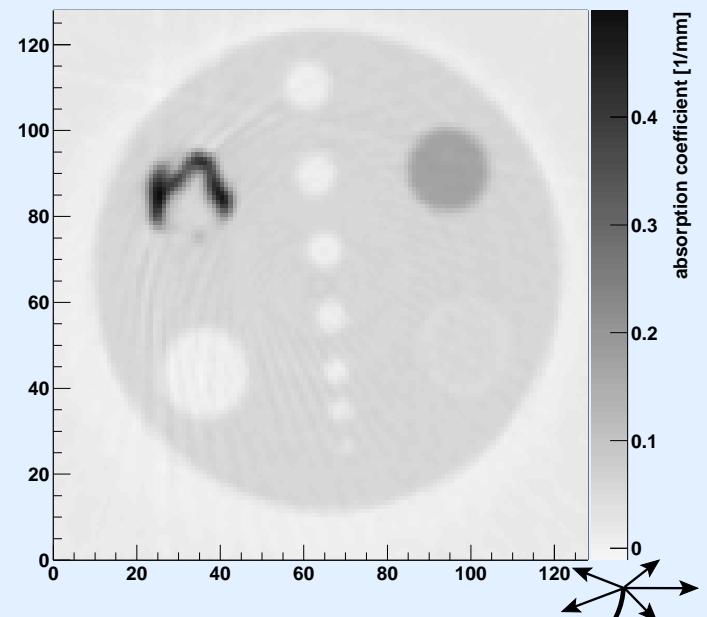
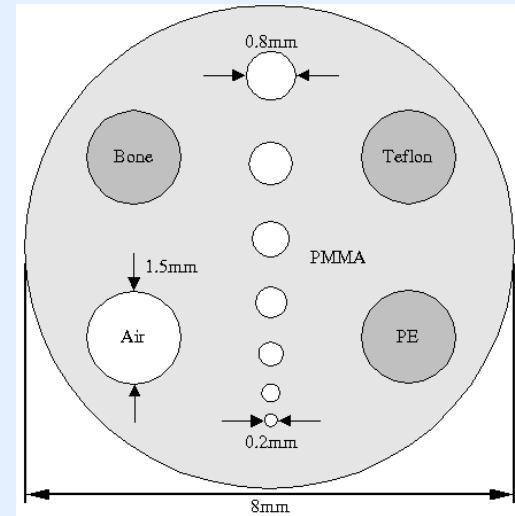
Conventional CT images

- Object is made out of an 8 mm PMMA rod; the 1.5 mm holes are filled with bone, PA, Teflon, and air
- Measurement was done with minimal threshold \Rightarrow all photons are used
- Differences in attenuation between materials clearly visible
- 0.2 mm-hole can be resolved
- Beam hardening artefacts produced by bone

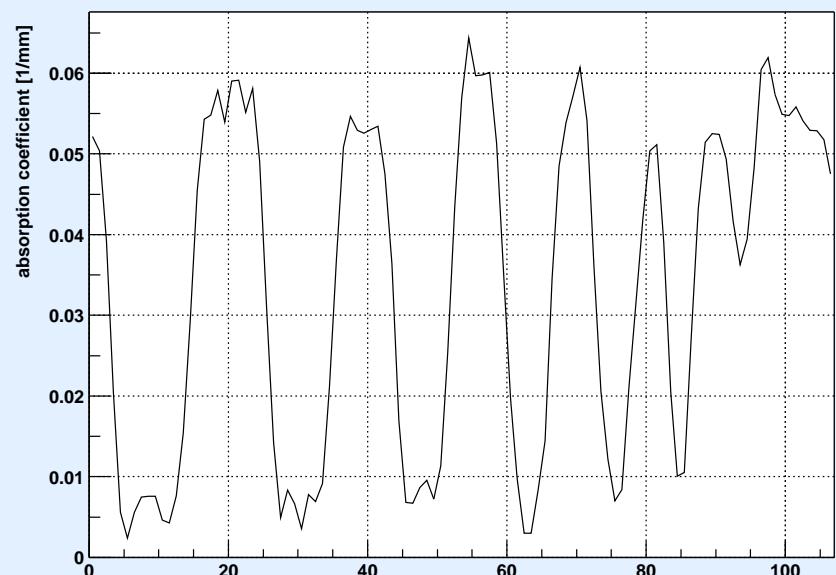
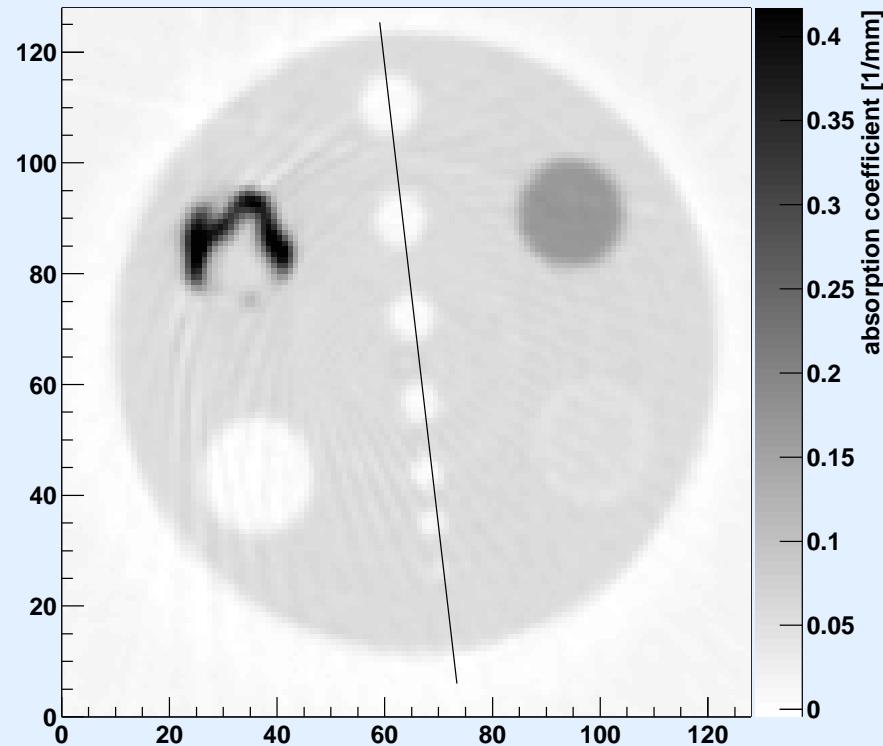


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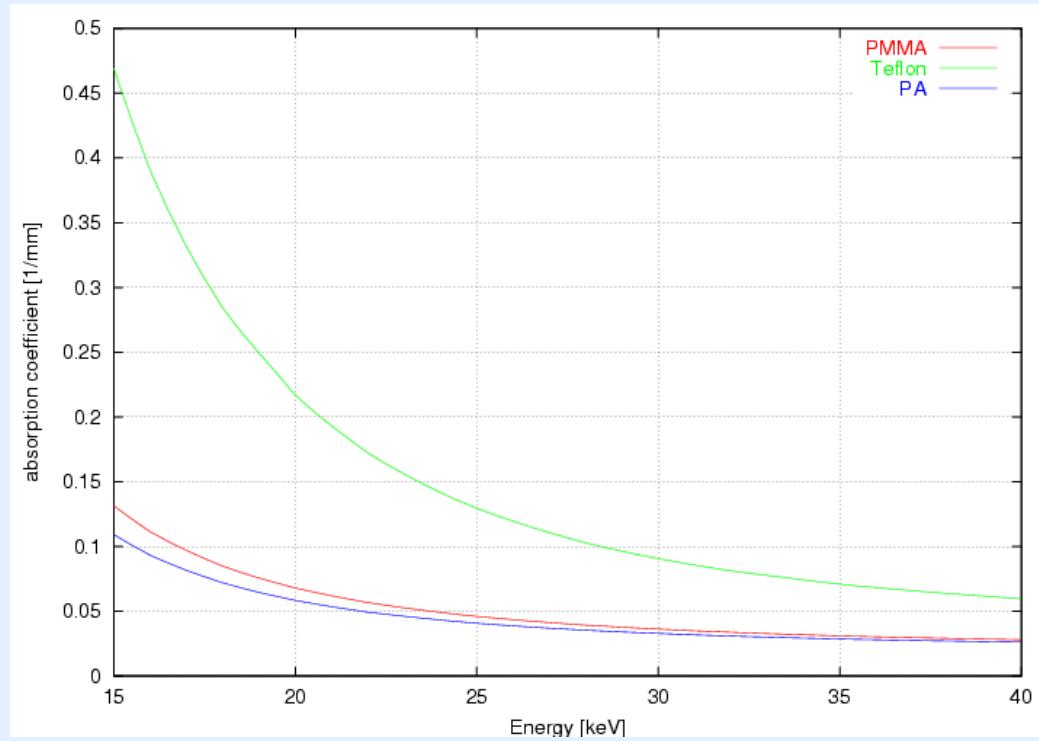
Evaluation via linescan



Linescan shows that contrast diminishes with diameter of holes

How can we use the energy threshold?

- μ changes with photon-energy
- Use Medipix1 to measure μ with respect to energy, which is *not* possible with integrating detectors

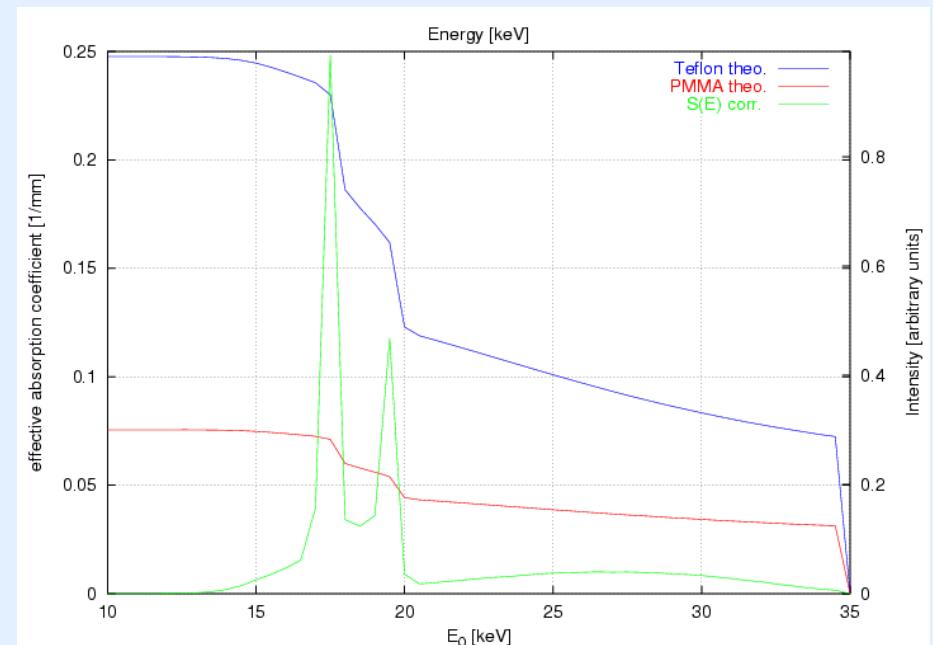


Dependency of μ_{eff} on energy threshold

- The measured μ_{eff} depends on the used spectrum $S(E)$ and the energy range of the photons:

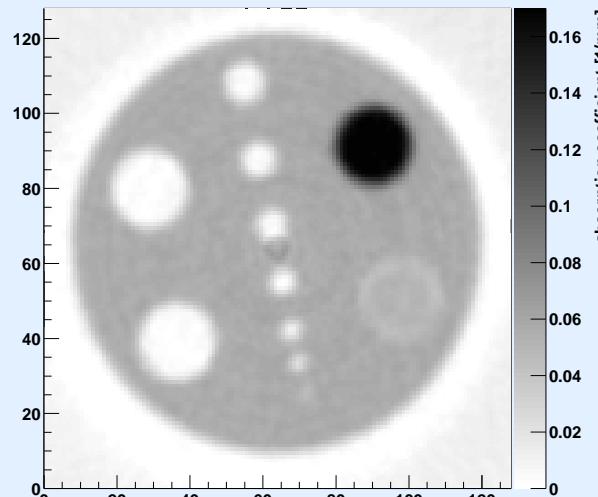
$$\mu_{\text{eff}} = \frac{\int_{E_0}^{\infty} S(E) \mu(E) dE}{\int_{E_0}^{\infty} S(E) dE}$$

- E_0 can be varied when using the Medipix1
- μ_{eff} is shown for Teflon (blue) and PMMA (red) for the corrected and simulated spectrum of Mo at 35 keV (2 mm Al and 0.3 mm Mo as filter)

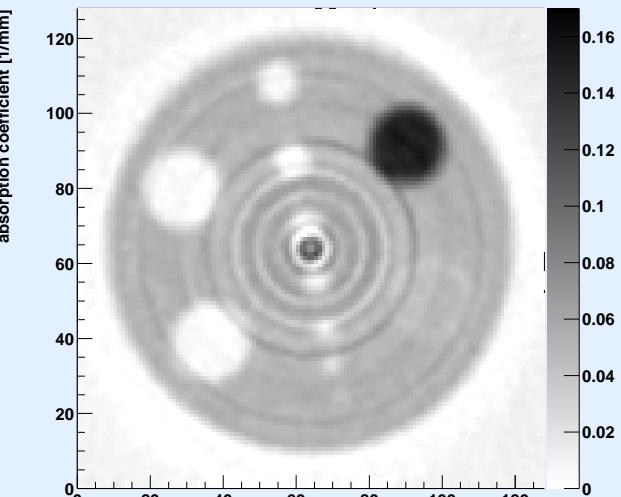


CT measurements with E_0 variation

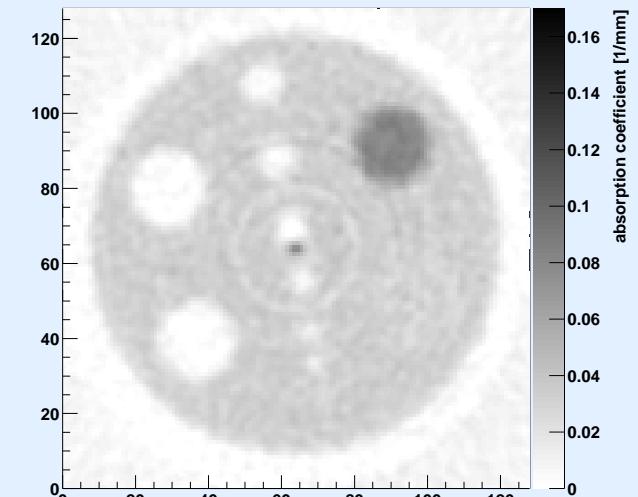
- We did CT-measurements at 3 different cut-off energies E_0 with the object described earlier (at 35 kV with 2 mm Al, 0.3 mm Mo)
- Images were evaluated for contrast changes and for the absolute value of $\mu_{\text{eff}}(E_0)$



$E_0 = 11.5 \text{ keV}$



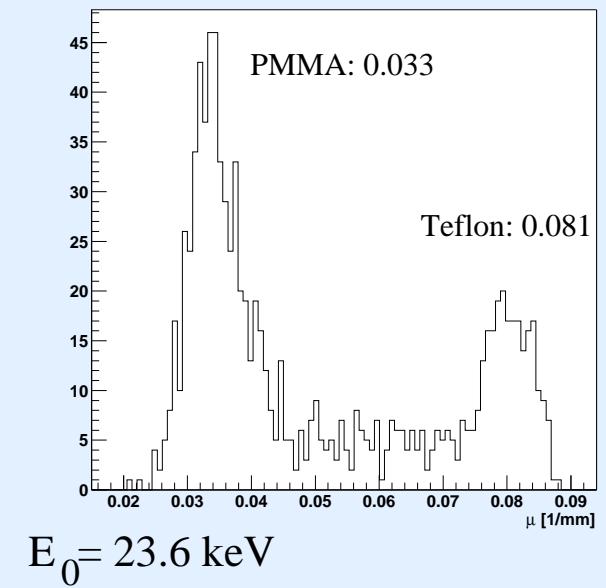
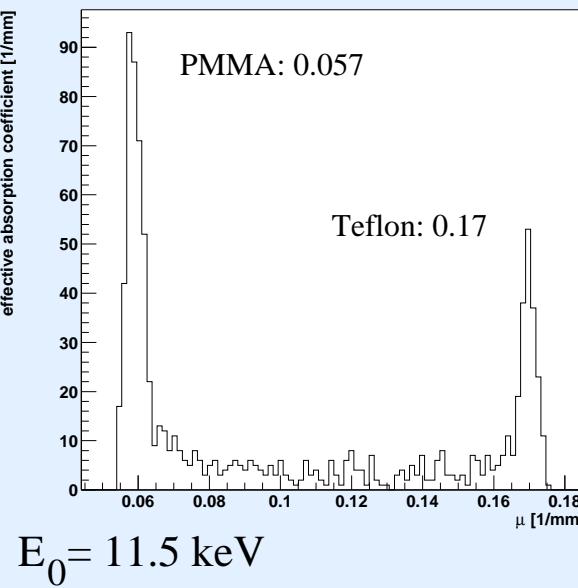
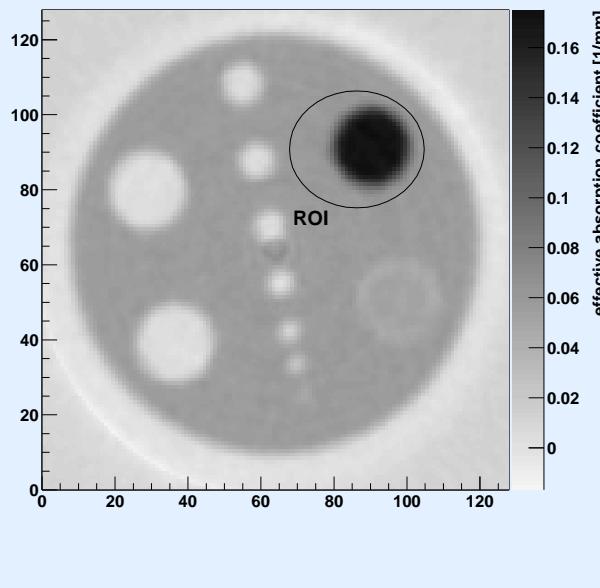
$E_0 = 16.5 \text{ keV}$



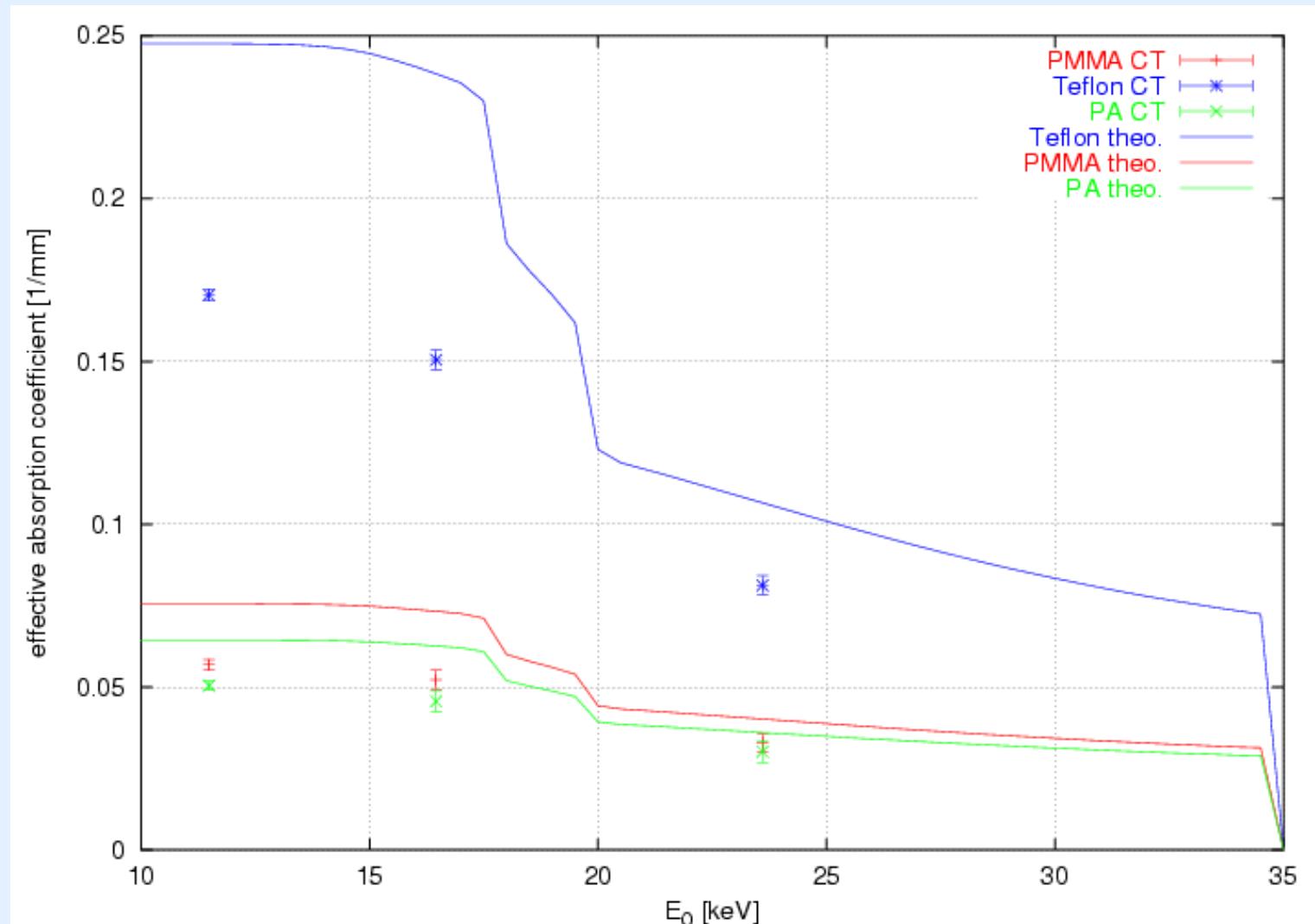
$E_0 = 23.6 \text{ keV}$

Effects on contrast

- Contrast between an object with absorption μ and its background (μ_{bg}) is defined by: $C = \frac{\mu - \mu_{\text{bg}}}{\mu_{\text{bg}}}$
- The contrast of Teflon to PMMA changes from 2.0 to 1.47

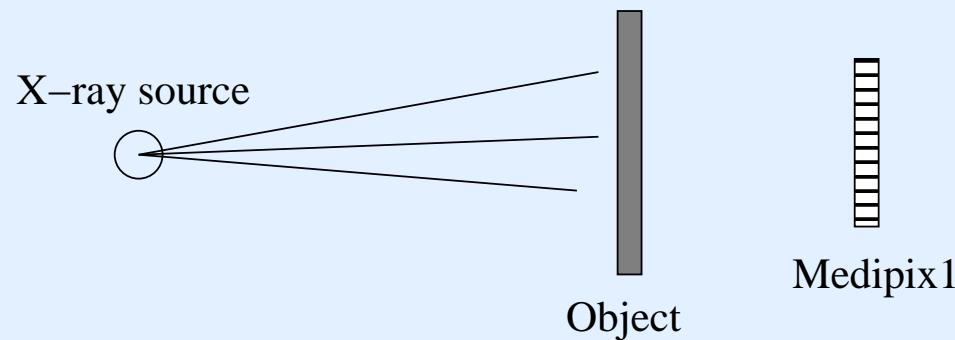


Comparison of measured $\mu_{\text{eff}}(E_0)$ with theory



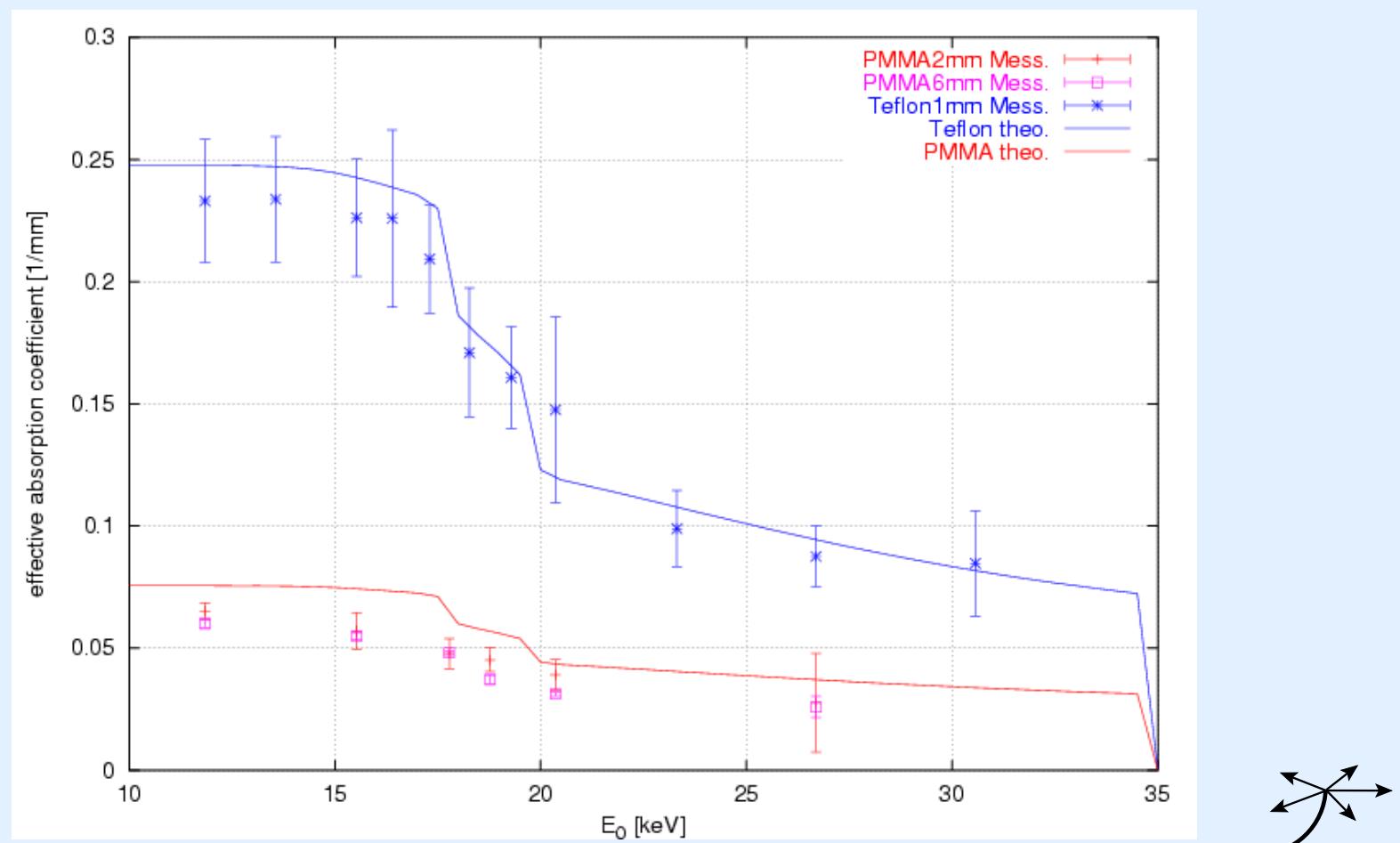
Similar non-CT measurements of $\mu_{\text{eff}}(E_0)$

- Simple non-CT measurements were done to reproduce theoretical $\mu_{\text{eff}}(E_0)$
- Differences are smaller compared to the CT values



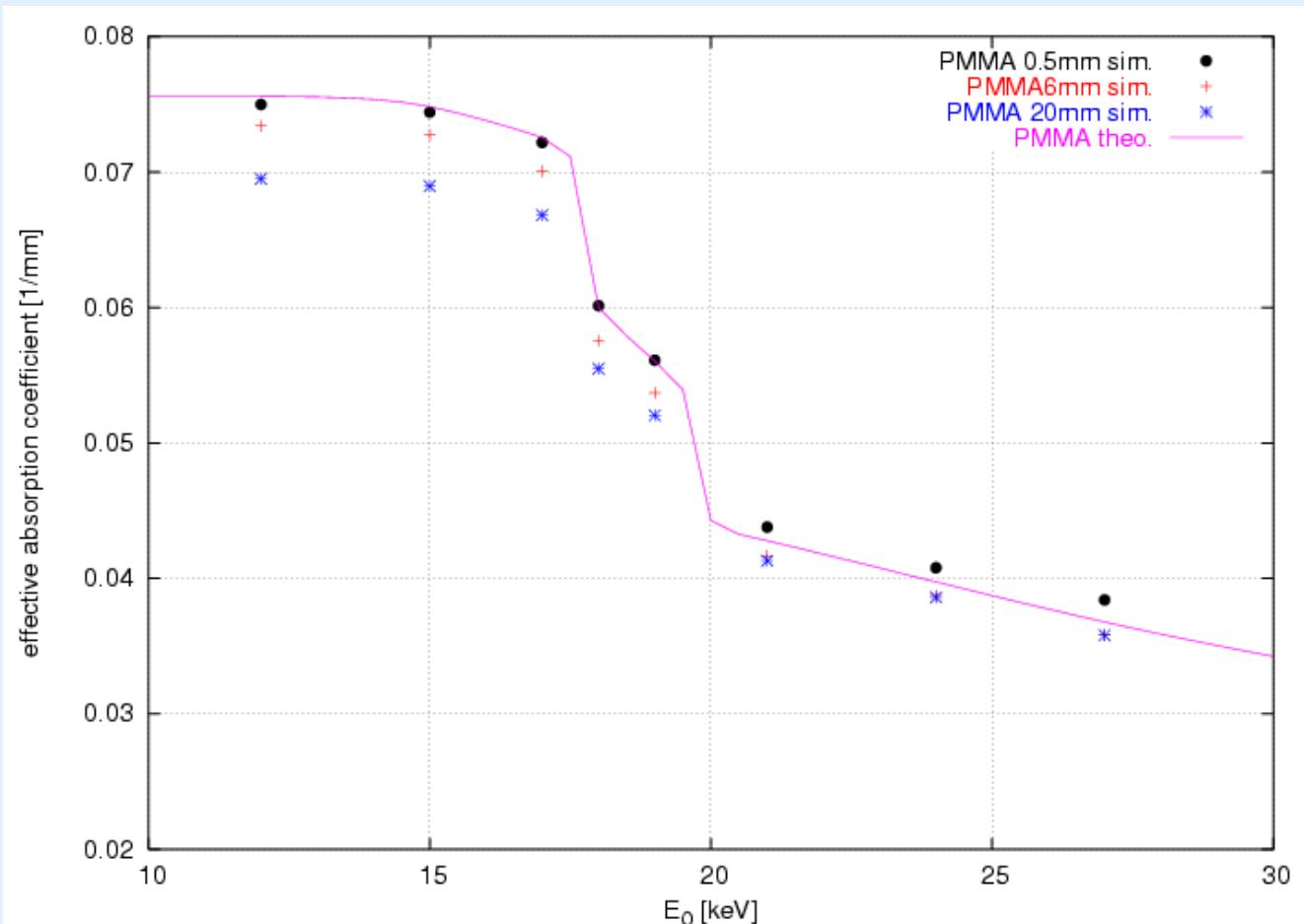
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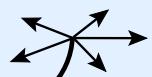
Simulation results

- Simple measurement was simulated for different material thicknesses (ROSI)

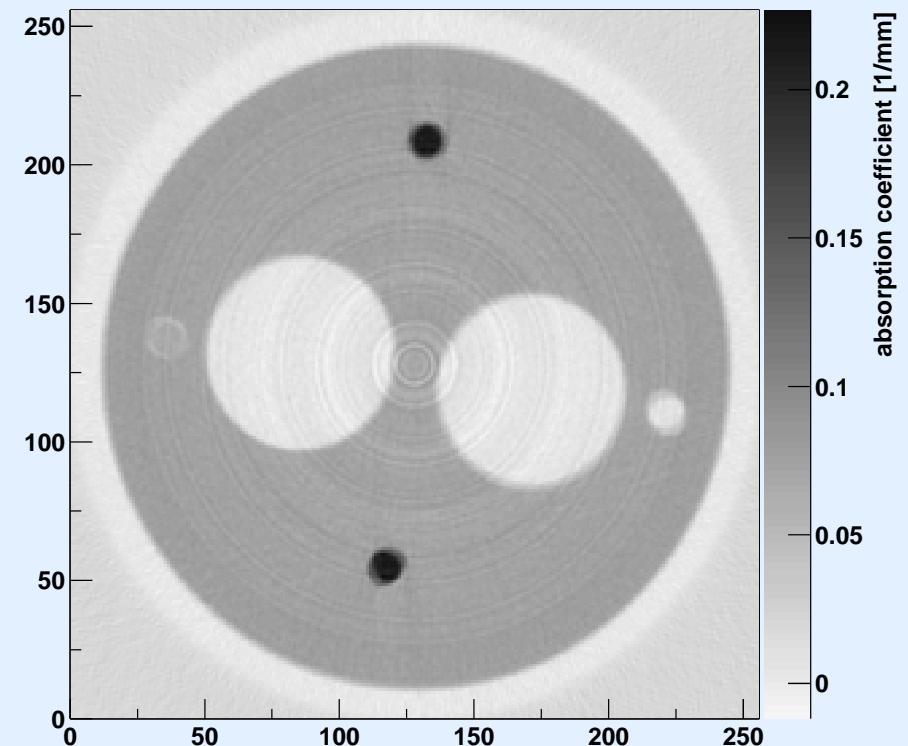
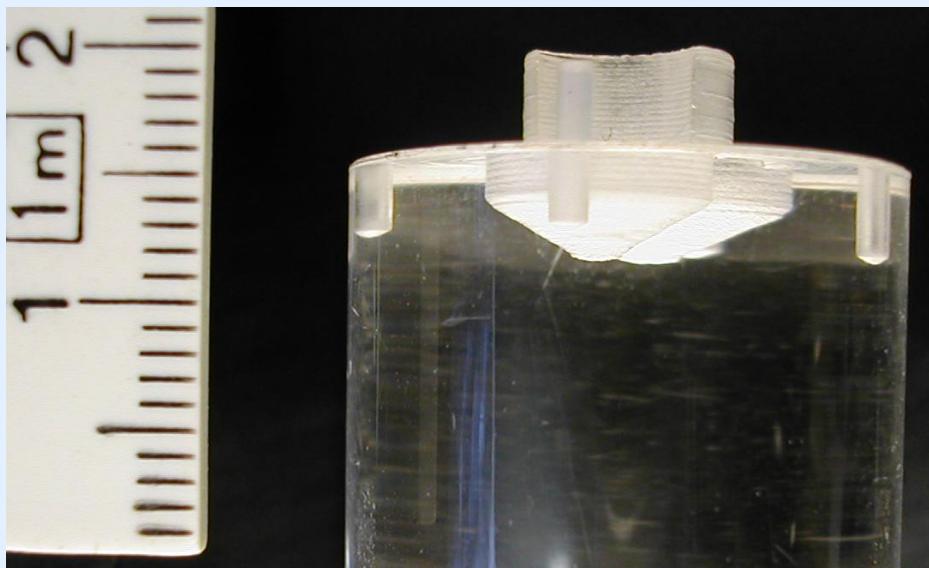


Evaluation of measurements and simulation

- In both measurements were differences between the measured data and the theoretical curve
- Possible reason could be the photon spectrum $S(E)$ because it isn't measured but obtained from a simulation
- One reason for the differences is beam hardening:
 - The low-energy-photons of the spectrum have a shorter absorption length
 - Resulting beam is more penetrating $\Rightarrow \mu_{\text{eff}}$ is smaller
 - Effect increases with increasing object thickness
 - A high E_0 causes a decrease of the impact of beam hardening



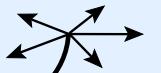
CT with a large virtual detector



Medipix1 was moved to 3 adjacent positions at each angle
to imitate a larger detector (1110 measurements)

Conclusion and outlook

- Small scale CT is possible with the Medipix1
- Even with simple techniques quite good results can be obtained
- Energy threshold can be used to measure $\mu_{\text{eff}}(E_0)$
- Higher photon energies combined with different conversion materials will be used in future measurements
- Looking forward to Medipix2 (two thresholds, larger sensitive area, smaller and more pixels)



Thanks to . . .

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